Abstracts

Millimeter wave measurements of temperature dependence of complex permittivity of dielectric plates by a cavity resonance method

Y. Kobayashi and T. Shimizu. "Millimeter wave measurements of temperature dependence of complex permittivity of dielectric plates by a cavity resonance method." 1999 MTT-S International Microwave Symposium Digest 99.4 (1999 Vol. IV [MWSYM]): 1885-1888 vol.4.

A novel circular cavity resonance method based on a rigorous analysis by the mode matching technique is proposed to measure the temperature dependences of complex permittivity of low loss dielectric plates accurately in the millimeter wave range 30-100 GHz. The measured results for GaAs substrates verify the usefulness.

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